ABSTRACT OF THE DISCLOSURE

A defective pixel detecting method and an image-pickup apparatus having a plurality of solidstate image-pickup devices each receiving respective one of spectral lights obtained by separating light incident to the image-pickup apparatus, generating, for each spectral light, a value relating to an inspected defective pixel on an associated solid-state imagepickup device located at a corresponding same imagepickup point among the plurality of solid-state imagepickup devices based on a signal level produced from the inspected pixel and signal levels produced from a plurality of pixels of the associated solid-state image-pickup device in the vicinity of the inspected pixel, and determining the solid-state image-pickup device that generated a defective pixel based on the values obtained with respect to the plurality of solidstate image-pickup devices.